


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/631,319	RHEE, SHIN W.	
	Examiner	Art Unit	
	Y Quach Lee	2875	

SEARCHED			
Class	Subclass	Date	Examiner
362	Updated Search	2/22/2005	YMY

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
362	Above	2/22/2005	YMY

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
NONE	2/22/2005	YMY